

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

M. ISHIBASHI et al

Serial No. 09/616,076

Group Art Unit: 2881

Filed: July 13, 2000

Examiner: S. Payne

For: PROBE FOR SCANNING PROBE LITHOGRAPHY
AND MAKING METHOD THEREOF

SUPPLEMENTAL AMENDMENT

Commissioner for Patents
Washington, D.C. 20231

Sir:

Further to the Amendment filed December 13, 2001, please
amend the above-identified application as follows.

IN THE CLAIMS

Please rewrite claims 6 and 14 as set forth below.

6. (Amended) A probe for scanning probe lithography as
claimed in claim 1,

wherein said fine needle is made of a hard
conductive material selected from the group consisting of
titanium, tungsten, molybdenum, titanium carbide, tungsten
carbide, molybdenum carbide, hydrogenated carbon, titanium

